AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

1-3 (Canceled).

4. (Original) A method of forming a semiconductor film, comprising the steps of:
forming an amorphous semiconductor film on a substrate having an insulating
surface;

introducing a catalytic substance for accelerating crystallization into a surface of the amorphous semiconductor film;

applying first energy to the amorphous semiconductor film to crystallize the amorphous semiconductor film into a crystalline semiconductor film; and

applying second energy to the crystalline semiconductor film so that nearly all crystal orientation angle differences between adjacent crystal grains are present in the ranges of less than 10° or 58°-62°, wherein the crystallinity of the crystalline semiconductor film is increased to be turned into a polycrystalline semiconductor film.

5. (Original) A method according to claim 4, wherein the first energy is heat energy and the second energy is strong light.

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6. (Original) A method according to claim 5, wherein the energy density of the

strong light is such that after irradiation of the strong light, the proportion of the crystal

orientation angle difference between adjacent crystal grains of less than 10° or 58°-62° is

highest.

7. (Original) A method according to claim 4, wherein the semiconductor film is

made of silicon.

8. (Original) A method according to claim 4, wherein the catalytic substance is a

metal selected from the group consisting of Fe, Co, Ni, Cu, Ge, Pd, and Au, a compound

containing at least one of these metals, or a combination of at least one of these metals

and a compound containing at least one of these metals.

9. (Original) A method according to claim 4, wherein the concentration of the

catalytic substance at a surface of the amorphous semiconductor film is greater than or

equal to $1x10^{11}$ atoms/cm² and smaller than or equal to $1x10^{16}$ atoms/cm².

10. (Original) A method according to claim 5, wherein the strong light is excimer

laser light.

11-12 (Canceled).

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